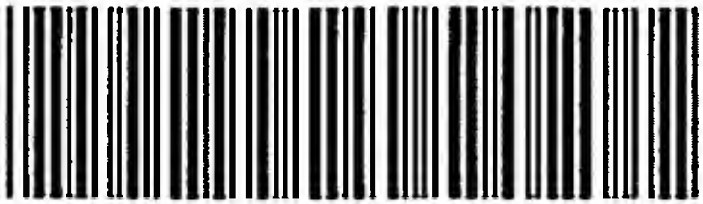


Search Notes



Application/Control No.

10/805,023

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

IKEDA ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	10/05	DN
	6		
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	10		
707	5		
713	200		
395	600		
	650		
	700		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I USP 1) PG Pub 2) Patent	10/05	DN
II FOREIGN 1. EPO 2. JPO 3. Derwent 4. IBM TDB		